

<b>Notice of References Cited</b>	Application/Control No. 10/647,106		Applicant(s)/Patent Under Reexamination BOOKER ET AL.	
	Examiner Qing Chen		Art Unit 2191	Page 1 of 1

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	W	Whaley, John, "Partial Method Compilation using Dynamic Profile Information," November 2001, ACM, pg. 166-179.				
	X	Tikir et al., "Efficient Instrumentation for Code Coverage Testing," July 2002, ACM, pg. 86-96.				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.